

SJ-FET

SSP20N60S / SSF20N60S 600V N-Channel MOSFET

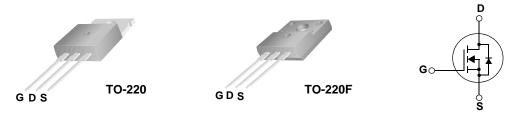
Description

SJ-FET is new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. SJ-FET is suitable for various AC/DC power conversion in switching mode operation for higher efficiency.

Features

- 650V @T_{.I} = 150°C
- Typ. $R_{DS(on)} = 0.16 \Omega$
- Ultra Low Gate Charge (typ. Q_q = 70nC)
- 100% avalanche tested



Absolute Maximum Ratings

Symbol	Parameter		SSP20N60S SSF20N60S		Unit	
V _{DSS}	Drain-Source Voltage		600		V	
I _D	Drain Current	- Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		20 12	20* 12*	A A
I _{DM}	Drain Current	- Pulsed	(Note 1)	60	60*	А
V _{GSS}	Gate-Source voltage		± 30		V	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		(Note 2)	600		mJ
I _{AR}	Avalanche Current		(Note 1)	te 1) 20		А
E _{AR}	Repetitive Avalanche Energy (Note 1)		(Note 1)	20.5		mJ
dv/dt	Peak Diode Recove	ry dv/dt	(Note 3)	4.5		V/ns
P _D	Power Dissipation	(T _C = 25°C) - Derate above 25°C		205 1.67	35 0.3	W W/°C
T _{J,} T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C	
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300		°C	

^{*} Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	SSP20N60S	SSF20N60S	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.6	3.6	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ.	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	62	°C/W

Flactrical Characteristics TC - 25°C

Symbol	Characteristics TC = 25°C	Conditions	Min	Тур	Max	Unit
Off Characteristics	•					
BVDSS	Drain-Source Breakdown Voltage	VGS = 0V, ID = 250μA, TJ = 25°C	600			V
		VGS = 0V, ID = 250μA, TJ = 150°C		650		V
ΔBVDSS / ΔTJ	Breakdown Voltage Temperature Coefficient	ID = 250µA, Referenced to 25°C		0.6		V/°C
IDSS	Zero Gate Voltage Drain Current	VDS = 600V, VGS = 0V VDS = 480V, TC = 125°C			1 10	μA μA
IGSSF	Gate-Body Leakage Current, Forward	Gate-Body Leakage Current, Forward VGS = 30V, VDS = 0V			100	nA
IGSSR	Gate-Body Leakage Current, Reverse	VGS = -30V, VDS = 0V			-100	nA
On Characteristics						
VGS(th)	Gate Threshold Voltage	VDS = VGS, ID = 250μA	2.5		4.5	V
RDS(on)	Static Drain-Source On- Resistance	VGS = 10V, ID = 5A		0.16	0.19	Ω
gFS	Forward Transconductance	VDS = 40V, ID = 5A (Note 4)		16		S
Dynamic Characteris	stics					
Ciss	Input Capacitance	VDS = 25V, VGS = 0V, f =		1440		pF
Coss	Output Capacitance	1.0MHz		300		pF
Crss	Reverse Transfer Capacitance			10		pF
Switching Characteri	istics					
td(on)	Turn-On Delay Time	VDD = 400V, ID = 5A RG =		25		ns
tr	Turn-On Rise Time	20Ω(Note 4, 5)		55		ns
td(off)	Turn-Off Delay Time			70		ns
tf	Turn-Off Fall Time			40		ns
Qg	Total Gate Charge	VDS = 480V, ID = 10A VGS		70	90	nC
Qgs	Gate-Source Charge	= 10V (Note 4, 5)		7.8		nC
Qgd	Gate-Drain Charge			9		nC
	Characteristics and Maximum Ratings					
IS						Α
ISM		Maximum Pulsed Drain-Source Diode Forward Current			60	Α
VSD	Drain-Source Diode Forward Voltage	VGS = 0V, IF = 10A		1	1.5	٧
trr	Reverse Recovery Time	<u> </u>		475		ns
Qrr				5.8		μC
Irrm				35		A

NOTES:

^{1.} Repetitive Rating: Pulse width limited by maximum junction temperature

The petitive rating. Fulse width immed by maximum junction 2. L=10.5mH, I_{Ag} =10A, VDD=150V, Starting TJ=25 °C 3. I_{SD} ≤1D, di/dt ≤ 200A/us, V_{DD} = 8V $_{DSS}$, Starting TJ = 25 °C 4. Pulse Test: Pulse width ≤ 300us, Duty Cycle ≤ 2%

^{5.} Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

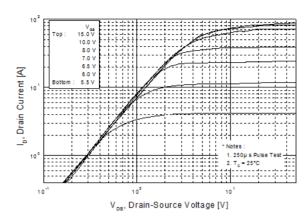


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

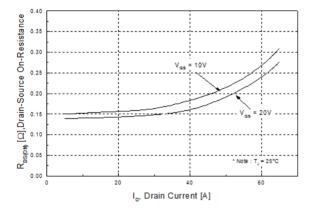


Figure 5. Capacitance Characteristics

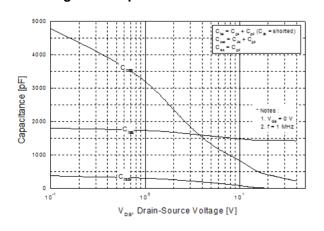


Figure 2. Transfer Characteristics

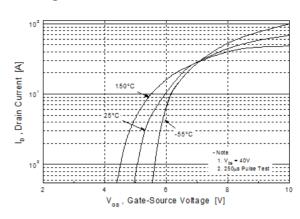


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

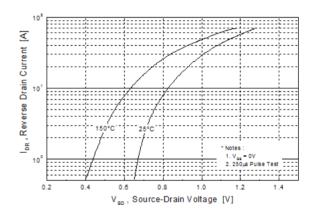
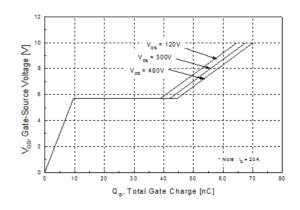


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

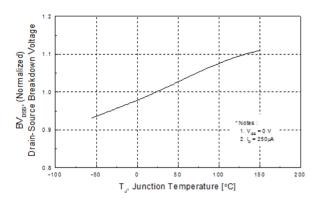


Figure 8. On-Resistance Variation vs. Temperature

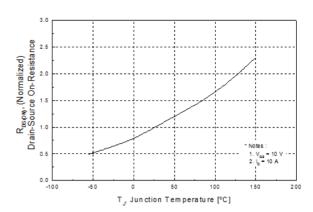


Figure 9-1. Safe Operating Area of SSP20N60S

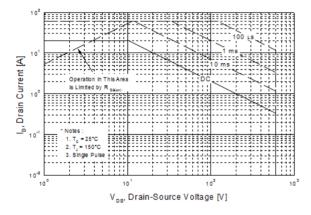


Figure 9-2. Safe Operating Area of SSF20N60S

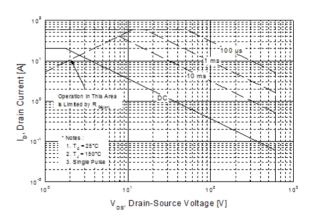
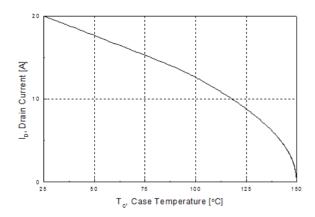


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 10-1. Transient Thermal Response Curve of SSP20N60S

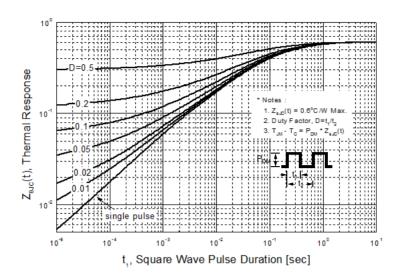
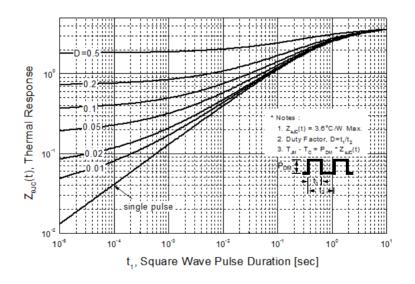
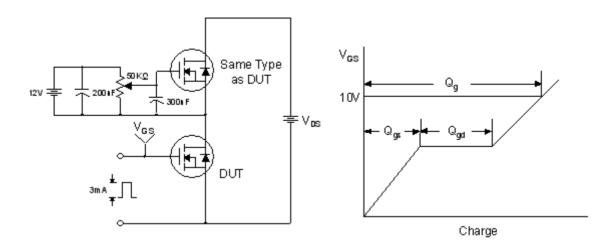


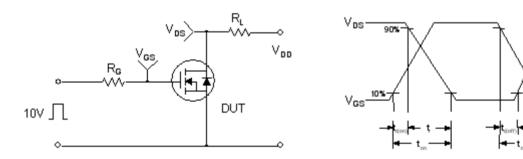
Figure 10-2. Transient Thermal Response Curve of SSF20N60S



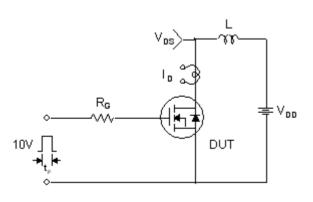
Gate Charge Test Circuit & Waveform

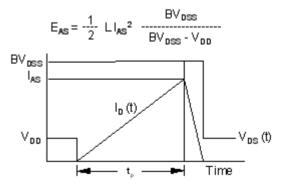


Resistive Switching Test Circuit & Waveforms

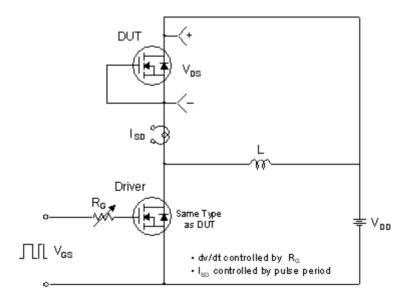


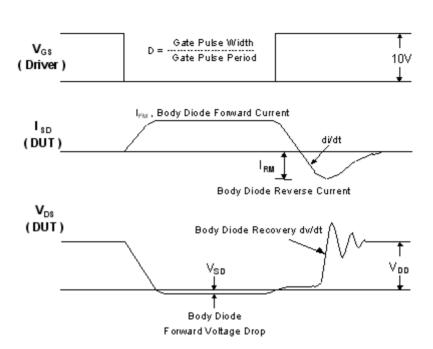
Unclamped Inductive Switching Test Circuit & Waveforms

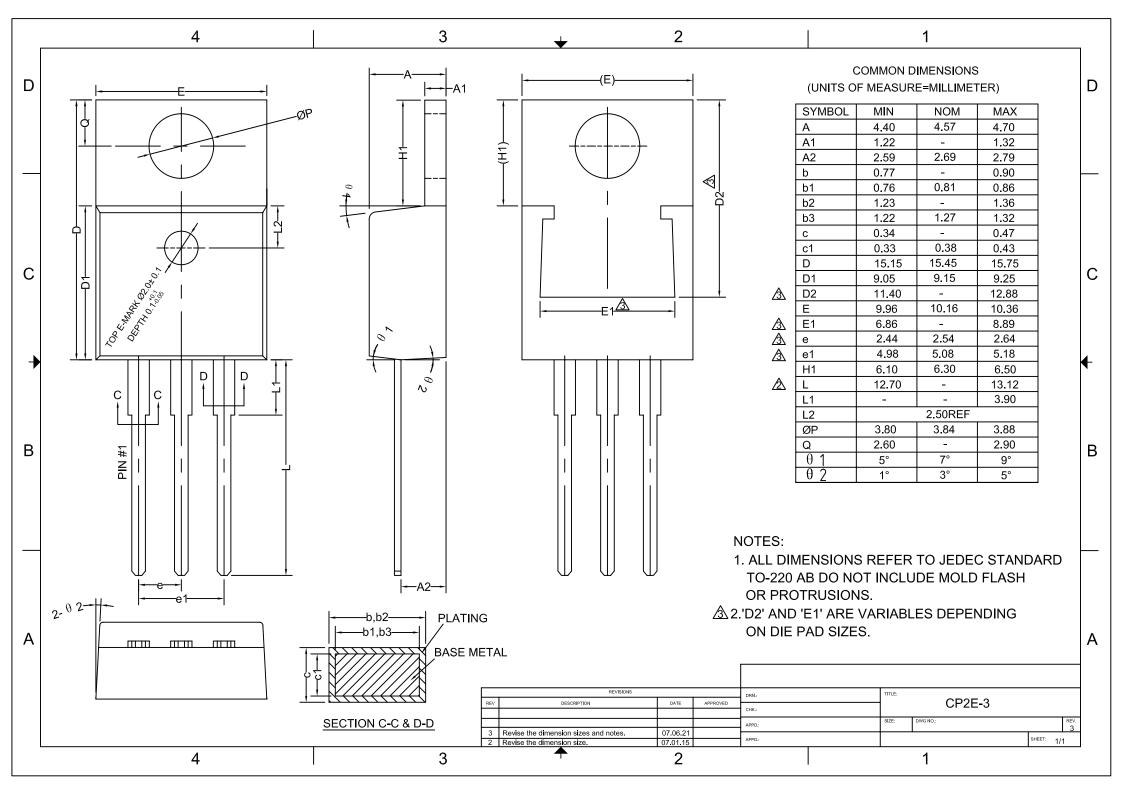


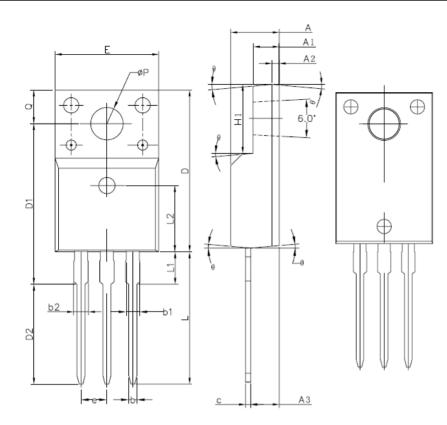


Peak Diode Recovery dv/dt Test Circuit & Waveforms









COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
Α	4.50	4.70	4.90	
A1	2.34	2.54	2.74	
A2	0.70 REF			
А3	2.56	2.56 2.76		
b	0.70	-	0.90	
b1	1.18	_	1.38	
b2	_	_	1.47	
С	0.45	0.50	0.60	
D	15.67	15.87	16.07	
D1	15.55	15.75	15.95	
D2	9.60	9.80	10.0	
E	9.96	10.16	10.36	
е	2.54BSC			
H1	6.48	6.68	6.88	
L	12.68	12.98		
L1	_	-	3.50	
L2	6.50REF			
øΡ	3.08	3.18	3.28	
Q	3.20	_	3.40	
θ	3°	5°	7°	

